

## TRADEMARK ASSIGNMENT COVER SHEET

Electronic Version v1.1  
Stylesheet Version v1.2

ETAS ID: TM337114

<b>SUBMISSION TYPE:</b>	NEW ASSIGNMENT		
<b>NATURE OF CONVEYANCE:</b>	ASSIGNMENT OF THE ENTIRE INTEREST AND THE GOODWILL		
<b>CONVEYING PARTY DATA</b>			
<b>Name</b>	<b>Formerly</b>	<b>Execution Date</b>	<b>Entity Type</b>
Wentworth Laboratories, Inc.		11/13/2014	CORPORATION: CONNECTICUT
<b>RECEIVING PARTY DATA</b>			
<b>Name:</b>	WinWay Technology Co., Ltd.		
<b>Street Address:</b>	No. 68, Chuangyi S. Rd.		
<b>Internal Address:</b>	Second District of Nanzih Export Processing Zone		
<b>City:</b>	Nanzih Dist., Kaohsiung City		
<b>State/Country:</b>	TAIWAN		
<b>Postal Code:</b>	81156		
<b>Entity Type:</b>	CORPORATION: TAIWAN		
<b>PROPERTY NUMBERS Total: 2</b>			
<b>Property Type</b>	<b>Number</b>	<b>Word Mark</b>	
<b>Registration Number:</b>	2620346	PROBEABILITY	
<b>Registration Number:</b>	2144860	COBRA	
<b>CORRESPONDENCE DATA</b>			
<b>Fax Number:</b>	2037822889		
<i>Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.</i>			
<b>Phone:</b>	203.498.4347		
<b>Email:</b>	fduffin@wiggins.com		
<b>Correspondent Name:</b>	Francis J. Duffin, Wiggins and Dana LLP		
<b>Address Line 1:</b>	One Century Tower, P.O. Box 1832		
<b>Address Line 4:</b>	New Haven, CONNECTICUT 06508-1832		
<b>ATTORNEY DOCKET NUMBER:</b>	401208/GEN001		
<b>DOMESTIC REPRESENTATIVE</b>			
<b>Name:</b>	Francis J. Duffin, Wiggins and Dana LLP		
<b>Address Line 1:</b>	One Century Tower, P.O. Box 1832		
<b>Address Line 4:</b>	New Haven, CONNECTICUT 06508-1832		
<b>NAME OF SUBMITTER:</b>	Francis J. Duffin		

CH \$65.00 2620346

<b>SIGNATURE:</b>	/fjd/
<b>DATE SIGNED:</b>	04/02/2015
<b>Total Attachments: 9</b> source=WLI to WWTCL#page1.tif source=WLI to WWTCL#page2.tif source=WLI to WWTCL#page3.tif source=WLI to WWTCL#page4.tif source=WLI to WWTCL#page5.tif source=WLI to WWTCL#page6.tif source=WLI to WWTCL#page7.tif source=WLI to WWTCL#page8.tif source=WLI to WWTCL#page9.tif	

## INTELLECTUAL PROPERTY ASSIGNMENT AGREEMENT

This INTELLECTUAL PROPERTY ASSIGNMENT AGREEMENT (this "Agreement"), dated as of November 13, 2014, is entered into by and between WinWay Technology Co., Ltd., a Taiwanese corporation (the "Purchaser"), and Wentworth Laboratories, Inc., a Connecticut corporation (the "Seller"). Capitalized terms used but not defined herein have the meanings ascribed to such terms in the Purchase Agreement (as defined below).

WHEREAS, the Purchaser and the Seller have entered into an Asset Purchase Agreement dated as of the date hereof (the "Purchase Agreement"); and

WHEREAS, pursuant to the Purchase Agreement, the Seller has agreed to sell, transfer and convey to the Purchaser, and the Purchaser has agreed to purchase from the Seller, among other things, all of the right, title and interest of the Seller or Affiliate of the Seller (as applicable) in (i) all of the patents, patent applications and patent rights to inventions that are relevant to the Business and identified in Schedule 1.1(a) of the Purchase Agreement (ii) all of the trade secrets, know-how, BKMs, software licenses and other Intellectual Property and Intellectual Property Rights that are relevant to the Business and described in Schedule 1.1(b) of the Purchase Agreement and (iii) all goodwill of the Business (collectively, the "Transferred IP").

NOW, THEREFORE, for good and valuable consideration, the receipt and sufficiency of which are hereby acknowledged, the parties hereto, intending to be legally bound hereby, agree as follows:

1. Conveyance and Acceptance. In accordance with the provisions of the Purchase Agreement, the Seller, for itself and its Affiliates, hereby sells, transfers, conveys and assigns to the Purchaser, and the Purchaser hereby purchases, takes delivery of and acquires from the Seller, all of the Seller's right, title and interest, free and clear of all Encumbrances (other than licenses granted pursuant to the Contracts listed in Parts 2.6(a)(i) and 2.6(a)(ii) of the Disclosure Schedule or entered into in the ordinary course of business), in, to and under the Transferred IP.

2. Authorization. The Seller, for itself and its Affiliates, hereby authorizes and requests any official of any state or country whose duty is to issue intellectual property registrations, to (a) issue all registrations from any applications for registrations and (b) transfer any applications or registrations, as applicable, in each case that are included in the Transferred IP, to the Purchaser at the Purchaser's expense.

3. Further Assurances. The Seller, for itself and its Affiliates, successors and assigns, hereby covenants and agrees to execute and deliver such other instruments of sale, conveyance, assignment or transfer and take such other actions as may be reasonably requested by the Purchaser to more fully effectuate the sale, conveyance, assignment and transfer to the Purchaser, or its successor and assigns, of the Seller's or its Affiliate (as applicable) right, title and interest in the Transferred IP hereby sold, conveyed, assigned and transferred to the Purchaser, or intended so to be.

4. Miscellaneous.

(a) This Agreement shall be binding upon and inure to the benefit of the parties hereto and their respective successors and assigns.

(b) This Agreement (including any claim or controversy arising out of or relating to this Agreement) shall be governed by, interpreted under, and construed and enforced in accordance Section 10.10 of the Purchase Agreement.

(c) This Agreement may be amended or modified only by a written instrument executed by the Purchaser and the Seller.

(d) If any term, provision, covenant or restriction of this Agreement is held by a court of competent jurisdiction or other authority to be invalid, void, unenforceable or against its regulatory policy, such determination shall not affect the enforceability of any others or the remainder of this Agreement.

(e) This Agreement may be executed and delivered by facsimile or other electronic transmission, in multiple counterparts, each of which shall be considered one and the same agreement and shall become effective when a counterpart hereof shall have been signed by each of the parties hereto and delivered to the other party.

*[Remainder of page intentionally left blank. Signature page follows.]*

IN WITNESS WHEREOF, the parties hereto have caused this Agreement to be executed by their respective officers thereunto duly authorized as of the date first above written.

**PURCHASER:**

WinWay Technology Co., Ltd.

By: *[Handwritten Signature]*

Name:

Title:

**SELLER:**

Wentworth Laboratories, Inc.

By: \_\_\_\_\_

Name:

Title:

*[Signature Page to Intellectual Property Assignment Agreement]*

IN WITNESS WHEREOF, the parties hereto have caused this Agreement to be executed by their respective officers thereunto duly authorized as of the date first above written.

**PURCHASER:**

**WinWay Technology Co., Ltd.**

By: \_\_\_\_\_  
Name:  
Title:

**SELLER:**

**Wentworth Laboratories, Inc.**

By: \_\_\_\_\_  
Name:  
Title:

*[Signature Page to Intellectual Property Assignment Agreement]*

**SCHEDULE 1.1(B)**

**TRANSFERRED IPS**

**(see attached)**

Owner Name	Trademark Name	File Date	App Number	Reg. No.	Reg. Date	Next Renewal Date	Goods	Country Name	Trademark Status
Wentworth Laboratories, Inc.	COBRA	07-Nov-94	74/595669	2144860	17-Mar-98	17-Mar-18	Test probe electrical contacts and holder therefor for probing integrated circuits, semiconductor devices and the like	United States of America	Renewed
Wentworth Laboratories, Inc.	COBRA	01-Aug-95	95583083	95583083	19-Jan-96	01-Aug-16	Apparatus for testing, electric contacts and their carriers for probe circuits, for probing electronic circuits, integrated, semiconductor devices, and other devices analogue	France	Renewed
Wentworth Laboratories, Inc.	COBRA	07-Mar-96	2060390	2060390	17-Oct-97	17-Mar-17	Test probe apparatus, test probe electrical contacts and holders therefor, for probing integrated circuits, semi-conductor devices; test equipment, parts and fittings	United Kingdom	Renewed
Wentworth Laboratories, Inc.	COBRA	13-Mar-96	867103	592239	15-Mar-96	15-Mar-16	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like	Benelux	Renewed
Wentworth Laboratories, Inc.	VENOM	05-Jul-99	102101	TMA 156 82	15-Jul-02	15-Jul-17	Test probe electrical contacts and holder therefor, for probing integrated circuits, semi-conductor devices and the like	Canada	Registered
Wentworth Laboratories, Inc.	PROBEABILITY	13-Mar-01	76/224886	2620346	17-Sep-02	17-Sep-22	Publications, namely, newsletters concerning semiconductor device test probes and semiconductor test probe equipment, semiconductor device test probes and semiconductor test Publications, namely, newsletters concerning semiconductor device test probes and semiconductor test probe equipment, semiconductor device test probes and semiconductor test Publications, namely, newsletters concerning semiconductor device test probes and semiconductor test probe equipment, semiconductor device test probes and semiconductor test	United States of America	Renewed
Wentworth Laboratories, Inc.	PROBEABILITY	13-Mar-01	76/224886	2620346	17-Sep-02	17-Sep-22	Publications, namely, newsletters concerning semiconductor device test probes and semiconductor test probe equipment, semiconductor device test probes and semiconductor test Publications, namely, newsletters concerning semiconductor device test probes and semiconductor test probe equipment, semiconductor device test probes and semiconductor test	United States of America	Renewed
Wentworth Laboratories, Inc.	PROBEABILITY	13-Mar-01	76/224886	2620346	17-Sep-02	17-Sep-22	Publications, namely, newsletters concerning semiconductor device test probes and semiconductor test probe equipment, semiconductor device test probes and semiconductor test Publications, namely, newsletters concerning semiconductor device test probes and semiconductor test probe equipment, semiconductor device test probes and semiconductor test	United States of America	Renewed



Wentworth Laboratories, Inc.	SABER	05-Nov-02	78/181650	2808606	27-Jan-04	27-Jan-04	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	United States of America	Renewed
Wentworth Laboratories, Inc.	SABER	05-Nov-02	78/181650	2808606	27-Jan-04	27-Jan-04	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	United States of America	Renewed
Wentworth Laboratories, Inc.	SABER	05-Nov-02	78/181650	2808606	27-Jan-04	27-Jan-04	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	United States of America	Renewed
Wentworth Laboratories, Inc.	VENOM	16-May-03	3558009	3558009	28-Nov-04	27-Nov-14	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	China (People's Republic)	Registered
Wentworth Laboratories, Inc.	ACCUMAX	13-Apr-04	78/401147	2942080	19-Apr-05	19-Apr-15	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	United States of America	Registered
Wentworth Laboratories, Inc.	ACCUMAX	13-Apr-04	78/401147	2942080	19-Apr-05	19-Apr-15	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	United States of America	Registered
Wentworth Laboratories, Inc.	MICROMAX	06-Jul-06	78/923834	3339786	20-Nov-07	20-Nov-17	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	United States of America	Registered

Wentworth Laboratories, Inc.	MICROMAX	06-Jul-06	78/923834	3339786	20-Nov-07	20-Nov-17	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	United States of America	Registered
Wentworth Laboratories, Inc.	MICROMAX	12-Jul-06	T06/13670G	T06/13670G	18-Sep-07	12-Jul-16	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	Singapore	Registered
Wentworth Laboratories, Inc.	MICROMAX	14-Jul-06	95036553	1258251	16-Apr-07	16-Apr-17	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	Taiwan	Registered
Wentworth Laboratories, Inc.	ACCUMAX	17-Jul-06	5201785	5201785	10-Aug-07	17-Jul-16	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	European Community	Registered
Wentworth Laboratories, Inc.	ACCUMAX	17-Jul-06	T06/14230H	T06/14230H	21-Sep-07	17-Jul-16	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices; electrical testing equipment, namely, probe cards.	Singapore	Registered
Wentworth Laboratories, Inc.	ACCUMAX	18-Jul-06	95036529	255990	01-Apr-07	01-Apr-17	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	Taiwan	Registered
Wentworth Laboratories, Inc.	MACROMAX	19-Jul-06	T06/14357F	T06/14357F	02-Aug-07	19-Jul-16	Test probe electrical contacts and holders therefor and test probe high current large electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	Singapore	Registered
Wentworth Laboratories, Inc.	ACCUMAX	19-Jul-06	2006-67009	5076177	07-Sep-07	07-Sep-17	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; probe cards, probe card interfaces and fixtures to	Japan	Registered

Wentworth Laboratories, Inc.	MEGAMAX	15-Jun-07	77/207163	3437393	27-May-08	27-May-18	Test probe electrical contacts and holders therefor and test probe high current large electrical contacts and holders therefor, for probing integrated circuits, semiconductor Test probe electrical contacts and holders therefor and test probe high current large electrical contacts and holders therefor, for probing integrated circuits, semiconductor	United States of America	Registered
Wentworth Laboratories, Inc.	MEGAMAX	18-Jun-07	T07/13567D	T07/13567D	03-Oct-07	18-Jun-17	Test probe electrical contacts and holders therefor and test probe high current large electrical contacts and holders therefor, for probing integrated circuits, semiconductor	Singapore	Registered
Wentworth Laboratories, Inc.	MEGAMAX	21-Jun-07	096029195	1299525	01-Feb-08	01-Feb-18	Test probe electrical contacts and holders therefor and test probe high current large electrical contacts and holders therefor, for probing integrated circuits, semiconductor	Taiwan	Registered
Wentworth Laboratories, Inc.	MEGAMAX	26-Jun-07	2007-66782	5141688	13-Mar-08	13-Mar-18	Test probe electrical contacts and holders therefor and test probe high current large electrical contacts and holders therefor, for probing integrated circuits, semiconductor	Japan	Registered
Wentworth Laboratories, Inc.	SABER	20-Nov-07	6453096	6453096	30-Oct-08	20-Nov-17	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	European Community	Registered
Wentworth Laboratories, Inc.	SABER	21-Nov-07	2007-11743	11743			Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	Japan	Pending
Wentworth Laboratories, Inc.	SABER	21-Nov-07	096055080	1332679	16-Oct-08	16-Oct-18	Test probe electrical contacts and holders therefor, for probing integrated circuits, semiconductor devices and the like; electrical testing equipment, namely, probe cards.	Taiwan	Registered